

### **REMARKS**

Claims 1, 6-9, 15, 16 and 19-21 are pending. Claims 15 and 16 have been allowed by the Examiner. Claims 6, 7 and 19-21 have been canceled. Claims 1, 8 and 9 have been amended. Claims 1, 8, 9, 15 and 16 remain in this application.

### **REJECTIONS UNDER 35 USC § 102**

The Examiner has rejected claims 1, 6 and 9 under 35 USC § 102(b) as being anticipated by Yanagawa (JP 2000-114266). Claim 6 has been canceled. Claim 1 has been amended to incorporate the limitations of claims 6 and 7. These limitations include breakdown occurring at a higher voltage in the first portion and at a lower voltage in the second portion; and a breakdown voltage differential due to a difference in field plate strength. As the Examiner concedes, Yanagawa “does not specifically teach a breakdown voltage due to a difference in field plate strength.” (May 2, 2003 Office action, page 3.) Thus, Yanagawa does not anticipate the invention recited in amended claim 1.

Claim 9 has been amended to be dependent upon claim 1. For the reasons stated above, Yanagawa does not anticipate independent base claim 1. Similarly, Yanagawa cannot anticipate dependent claim 9 either. The Applicant respectfully submits that claims 1 and 9 should be allowed.

### **REJECTIONS UNDER 35 USC § 103**

The Examiner has rejected claim 7 under 35 USC 103(a) as being unpatentable over Yanagawa in view of Han et al. (US 5,907,181). Claim 7 has been canceled. The limitations of claim 7 have been incorporated into amended claim 1. The Examiner contends that Yanagawa discloses the device structure of claim 7 but does not specifically teach a breakdown voltage due to a difference in field plate strength; and that Han et al. discloses conductive contact M3'

extended over a dielectric layer 2 forming a field plate with different lengths thereby affecting the breakdown voltage. However, Han et al. discloses a field plate with different lengths affecting breakdown voltage of diodes only. Neither Yanagawa nor Han et al. disclose a field plate with different lengths affecting breakdown voltage of transistors or a transistor having a breakdown differential with a diode due to a difference in field plate length, as recited in amended claim 1. Thus, amended claim 1 is patentable over Yanagawa in view of Han et al.

The Examiner has rejected claim 8 under 35 USC 103(a) as being unpatentable over Yanagawa in view of Letavic et al. (US 5,969,387). Claim 8 has been amended to be dependent upon amended base claim 1, which the Applicant submits is allowable. Neither Yanagawa nor Han et al. disclose a field plate with different lengths affecting breakdown voltage of transistors or a transistor having a breakdown differential with a diode due to a difference in field plate length, as recited in amended claim 1. Nor does Letavic et al. disclose a field plate with different lengths affecting breakdown voltage of transistors or a transistor having a breakdown differential with a diode due to a difference in field plate length. Thus, claim 8, through amended claim 1, is patentable over Yanagawa in view of Letavic et al.

The Examiner has rejected claim 19 under 35 USC 103(a) as being unpatentable over Yanagawa in view of Han et al. Claim 19 has been canceled.

The Examiner has rejected claims 20 and 21 under 35 USC 103(a) as being unpatentable over Yanagawa in view of Letavic et al. Claims 20 and 21 have been canceled.

ALLOWABLE SUBJECT MATTER

Claims 15 and 16 have been allowed by the Examiner.

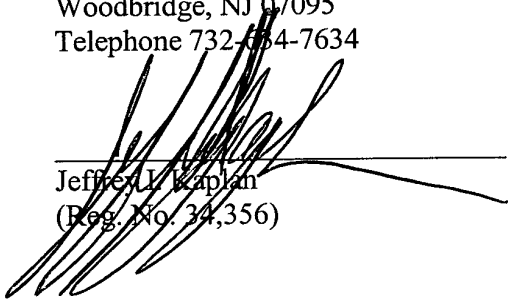
CONCLUSION

In view of the foregoing amendment and remarks, it is respectfully submitted that pending claims 1, 8, 9, 15 and 16 are allowable. Therefore, reconsideration and allowance are respectfully requested.

Respectfully submitted,

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DATED: July 10, 2003

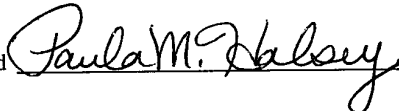
  
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Dated July 10, 2003

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